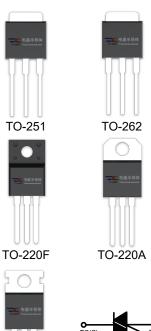
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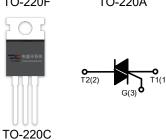
DESCRIPTION:

With high ability to withstand the shock loading of large current, TXDV808 series triacs provide high dv/dt rate with strong resistance to electromagnetic interface. With high commutation performances, 3 quadrants products especially recommended for use on inductive load.



MAIN FEATURES

Symbol	Value	Unit	
I _{T(RMS)}	8	Α	
VDRM /VRRM	600/800/1200	V	



ABSOLUTE MAXIMUM RATINGS

I	Parameter	Symbol	Value	Unit
Storage junction temperature range		T _{stg}	-40 - 150	$^{\circ}$
Operating junction temperature range		Tj	-40 - 125	$^{\circ}$
Repetitive peak off-state voltage (T _j =25℃)		V _{DRM}	600/800/1200	V
Repetitive peak reverse voltage (Tj=25℃)		V _{RRM}	600/800/1200	V
Non repetitive surge peak Off-state voltage		VDSM	V _{DRM} +100	V
Non repetitive peak reverse voltage		VRSM	V _{RRM} +100	V
RMS on-state current	TO-251/TO-220C TO-220A(Non-Ins) (Tc=100°C) TO-220A(Ins)/ TO-220F(Ins) (Tc=95°C) TO-262 (Tc=90°C)	I _{T(RMS)}	8	А
Non repetitive surge peak on-state current (full cycle, F=50Hz)		Ітѕм	80	Α

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I ² t value for fusing (tp=10ms)	l ² t	32	A^2s
Critical rate of rise of on-state current $(I_G=2\times I_{GT})$	dl/dt	50	A/µs
Peak gate current	I _{GM}	4	Α
Average gate power dissipation	P _{G(AV)}	1	W
Peak gate power	P _{GM}	5	W

ELECTRICAL CHARACTERISTICS (T_j =25 $^{\circ}$ C unless otherwise specified)

3 Quadrants

Symbol	Test Condition C	Quadrant		Value			Unit	
				TW	SW	CW	BW	Uill
lgт	V _D =12V R _L =33Ω	I - II -III	MAX	5	10	35	50	mA
V _{GT}	VD-12V KL-3312	I - II -III	MAX	1.5				V
V _{GD}	$V_D=V_{DRM}T_j=125$ °C RL=3.3KΩ	I - II -III	MIN	0.2			٧	
I _L I _G	I _G =1.2I _{GT}	I -III	MAX	20	25	50	70	mA
		II	IVIAA	25	35	70	90	IIIA
Ін	I _{TM} =100mA		MAX	15	20	40	60	mA
dV/dt	V _D =2/3V _{DRM} Gate Open T _j =125℃		MIN	50	200	500	1000	V/µs

4 Quadrants

Symbol	Test Condition	Quadrant		Val	Unit		
	rest Condition			С	В	Uill	
lor		I - II -III	MAX	25	50	mA	
I _{GT} V _D =12V R _L =33Ω	V _D =12V R _L =33Ω	IV	IVIAX	50	70		
VgT		ALL	MAX	1.	V		
V _{GD}	$V_D=V_{DRM}$ $T_j=125$ °C $R_L=3.3$ $KΩ$	ALL	MIN	0.	V		
IL	I _G =1.2I _{GT}	I -III-IV	MAX	50	50	70	m A
		II		70	90	- mA	
lн	I _{TM} =200mA		MAX	40	60	mA	
dV/dt	V _D =2/3V _{DRM} Gate Open T _j =125℃		MIN	200	500	V/µs	

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STATIC CHARACTERISTICS

Symbol	Parameter		Value(MAX)	Unit
V _{TM}	I _{тм} =11A tp=380µs	T _j =25℃	1.5	V
IDRM	VD =VDRM VR =VRRM	Tj=25℃	5	μΑ
I _{RRM}		T _j =125℃	1	mA

THERMAL RESISTANCES

Symbol	Parameter		Value	Unit
R _{th(j-c)}	junction to case(AC)	TO-251	2.1	
		TO-220A(Ins)	2.7	°C/W
		TO-220C/ TO-220A(Non-Ins)	1.8	
		TO-220F(Ins)	2.9	
		TO-262	3.0	



FIG.1: Maximum power dissipation versus RMS on-state current

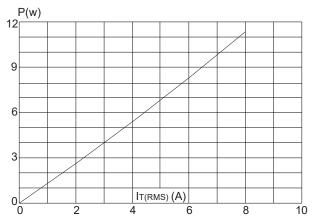


FIG.3: Surge peak on-state current versus number of cycles

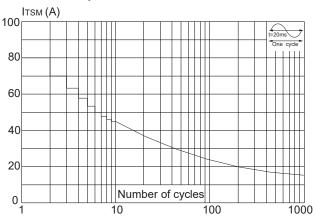


FIG.5: Non-repetitive surge peak on-state current for a sinusoidal pulse with width tp<20ms, and corresponging value of I²t (dI/dt < 50A/µs)

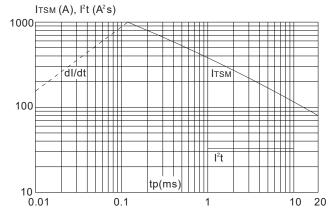


FIG.2: RMS on-state current versus case temperature

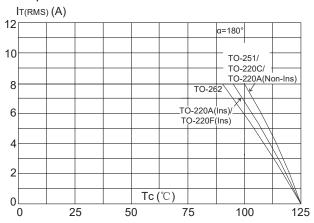


FIG.4: On-state characteristics (maximum values)

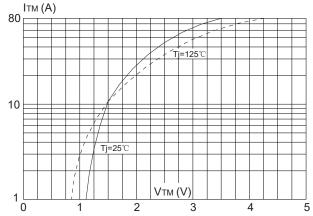


FIG.6: Relative variations of gate trigger current, holding current and latching current versus junction temperature

